Approval of Legal Metrology Experts and Management System Experts
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**Foreword**

This publication has been prepared by the Maintenance Group of the OIML Certification System (OIML-CS) Management Committee (MC).

The MC approved this Edition 2 of OIML-CS PD-02 by electronic ballot on 30 November 2018. This edition takes effect immediately upon publication.

This publication is directly related to the *Framework for the OIML Certification System (OIML-CS)* (OIML B 18 [1]) which contains the framework for the operation of the OIML-CS.

The text of this publication is based on the following documents:

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1 Introduction

1.1 The OIML Certification System (OIML-CS) has been established

   a) to promote the global harmonization, uniform interpretation and implementation of legal metrological requirements for measuring instruments and/or modules,

   b) to avoid unnecessary re-testing when obtaining national type evaluations and approvals, and to support the recognition of measuring instruments and/or modules under legal metrological control, while achieving and maintaining confidence in the results in support of facilitating the global trade of individual instruments, and

   c) to establish rules and procedures for fostering mutual confidence among participating OIML Member States and Corresponding Members in the results of type evaluations that indicate conformity of measuring instruments and/or modules, under legal metrological control, to metrological and technical requirements established in the applicable OIML Recommendation(s).

1.2 OIML B 18 Framework for the OIML Certification System (OIML-CS) [1] establishes the rules for a framework for the OIML-CS. OIML B 18 [1] is supplemented by a range of Operational Documents and Procedural Documents which are developed, maintained and approved by the OIML-CS Management Committee.

2 Scope

This document is one of a series of Operational Documents and Procedural Documents that define the rules for the operation of the OIML-CS.

This publication contains the procedures for the approval of Legal Metrology Experts and Management System Experts (Team Leaders), and on-going maintenance of the lists of experts.

These procedures relate to the framework for the OIML-CS as given in OIML B 18 [1], the Operational Rules as given in OD-01 [2] and OD-02 [3], and the Procedures as given in PD-01 [4], PD-03 [5], PD-04 [6], PD-05 [7], PD-06 [8], PD-07 [9] and PD-08 [10].
3 Terminology and abbreviations

The terminology and abbreviations defined in clause 3 of OIML B 18 [1] apply.

4 General

The criteria for qualification of Legal Metrology Experts and Management System Experts (Team Leaders) are performance oriented and flexible so that the suitability of a Legal Metrology Expert or Management System Expert can be judged on a case-by-case basis. Factors taken into consideration when deciding on the suitability of an expert include education, working knowledge and experience, training and assessment experience, personal skills and auditing skills.

5 Criteria for Legal Metrology Experts

The criteria for the qualification of Legal Metrology Experts that will participate in accreditation and peer assessments are defined in OD-01, 13.2.1 [2].

6 Criteria for Management System Experts

The criteria for the qualification of Management System Experts that will participate in peer assessments are defined in OD-01, 13.2.2 [2].

7 Nomination Process

7.1 Legal Metrology Experts

7.1.1 A person that considers they meet the qualification criteria to be a Legal Metrology Expert can apply to be a Legal Metrology Expert. They can apply to be an expert for a single category or for multiple categories of measuring instruments and the corresponding OIML Recommendation(s). Applications shall be made using the “Application to be a Legal Metrology Expert” form (hereafter referred to as the “LME Application Form”) which can be found on the OIML-CS website.

7.1.2 A completed LME Application Form shall be submitted to the Executive Secretary by the applicant. The Executive Secretary will review the LME Application Form to ensure that all of the relevant information has been provided. If information is missing, or further detail is required, the Executive Secretary will contact the applicant.
7.2 Management System Experts

7.2.1 Nominations from Accreditation Bodies

7.2.1.1 Persons to be included in the list of Management System Experts to participate in OIML peer assessments of Test Laboratories can be nominated by Accreditation Body signatories to the ILAC Mutual Recognition Arrangement or to a Regional Arrangement recognized by ILAC for the scope of “Testing ISO/IEC 17025”.

7.2.1.2 Persons to be included in the list of Management System Experts to participate in OIML peer assessments of OIML Issuing Authorities can be nominated by Accreditation Body signatories to the IAF Multilateral Recognition Arrangement (MRA) or to a Regional Arrangement recognized by IAF for the scope of “Product Certification ISO/IEC 17065”.

7.2.1.3 The nomination, along with evidence of an understanding of the OIML-CS and OIML D 32 [11] and/or OIML D 30 [12], as appropriate, can be submitted to the Executive Secretary by the MC member of the country of the Accreditation Body or by the ILAC or IAF secretariat, as appropriate.

7.2.2 Nominations from individuals

A person that considers they meet the qualification criteria to be a Management System Expert can apply to be a Management System Expert. Applications shall be made using the “Application to be a Management System Expert” form (hereafter referred to as the “MSE Application Form”) which can be found on the OIML-CS website. A completed MSE Application Form shall be submitted to the Executive Secretary by the applicant. The Executive Secretary will review the MSE Application Form to ensure that all of the relevant information has been provided. If information is missing, or further detail is required, the Executive Secretary will contact the applicant.

8 Review of application and decision

8.1 When the Executive Secretary is satisfied that all relevant information regarding the proposed expert has been provided the application will be sent to the Review Committee (RC). Members of the RC will review the application, either at an RC meeting or by correspondence, and will provide a recommendation to the MC to approve or reject the applicant. In the event that the RC makes a recommendation to approve the expert the Executive Secretary shall forward the documentation to the MC for approval, either at an MC meeting or by an electronic ballot. In the event that the RC does not make a recommendation to approve the expert the Executive Secretary shall notify the applicant of the decision and the reasons for rejection.
8.2 The MC votes on the approval of the applicant. If the applicant is not approved the Executive Secretary shall notify the applicant of the reasons for rejection. If the applicant is approved the Executive Secretary shall notify the applicant of his/her approval. The Executive Secretary shall request that the applicant signs a non-disclosure agreement which guarantees that all information received from and about assessed organizations is held in strict confidence. This agreement is signed with the BIML.

8.3 It is permitted to use a person that has not yet been approved as an expert in an accreditation assessment or peer assessment on the provision that an application to approve the person is made in conjunction with the application to be an OIML Issuing Authority/Test Laboratory. In doing so, the potential OIML Issuing Authority/Test Laboratory accepts the risk that the person may not be approved. In this instance the application to be an OIML Issuing Authority/Test Laboratory could be rejected or delayed.

9 Publication of Lists of Experts

9.1 When an applicant has been approved by the MC to be a Legal Metrology Expert and/or Management System Expert, the Executive Secretary will update the ILAC-IAF-OIML lists of experts published on the OIML-CS website.

9.2 When an expert is included on the list of Management System Experts, the Executive Secretary will send a notification to ILAC and/or IAF as appropriate.

10 Change of Scope

10.1 Experts may apply to request a change of scope, e.g. Legal Metrology Experts may wish to add or remove a measuring instrument category (and associated Recommendation) and Management System Experts may wish to add or remove assessment of OIML Issuing Authorities (ISO/IEC 17065 [13]) or Test Laboratories (ISO/IEC 17025 [14] [15]). Experts may also request to be removed from the lists.

Note: ISO and ILAC have issued a joint communiqué to re-confirm that a transition period, until 30 November 2020, will be provided for accredited laboratories to transition to the 2017 version of ISO/IEC 17025. Both the 2005 [15] and 2017 [14] versions of ISO/IEC 17025 will remain valid during the transition period (see http://ilac.org/latest_ilac_news/joint-iso-and-ilac-170252017-transition-communique-published/). However, each OIML Issuing Authority should confirm the transition process that applies within their jurisdiction with the relevant accreditation body.

10.2 Where a Legal Metrology Expert wishes to extend their scope to add a measuring instrument category (and associated Recommendation) or a Management System Expert wishes to add the
assessment of OIML Issuing Authorities or Test Laboratories, an application and the relevant supporting information shall be provided to the Executive Secretary. The application, and the information supporting the extension of scope, will be processed according to the procedures in 8.1 and 8.2 above.

10.3 Reductions in scope, or a request to be removed from the lists, do not need to undergo formal review by the RC. In these cases, the Executive Secretary will notify the MC and the published lists will be updated accordingly.

11 Monitoring of Experts

11.1 As outlined in OD-01, 13.4 [2], the on-going competence and suitability of experts shall be reviewed every 3 years.

11.2 The Executive Secretary shall contact each expert that is on the lists to determine if there has been any change in status, e.g. they no longer wish to be an expert, or if they would like to request a change of scope. Experts, as part of the review process, should provide evidence/information on the activities that they have been involved in during the 3-year period to support their on-going competence and suitability.

11.3 The Executive Secretary will compile a report outlining the evidence/information on the activities that the experts have been involved and any proposed changes to the status or scope of the experts. If, as part of the formal monitoring process, a Legal Metrology Expert wishes to extend their scope to include a measuring instrument category (and associated Recommendation) or a Management System Expert wishes to add the assessment of OIML Issuing Authorities or Test Laboratories, the relevant information shall also be provided to the Executive Secretary. The report, and any information supporting extensions to scope, will be provided to the RC for their review and recommendation according to 8.1 above. The recommendation(s) of the RC regarding the continued competence and suitability of the experts, including any extensions to scope, will be reported to the MC for their approval.

11.4 Requests to be removed from the lists do not need to undergo formal review by the RC. In these cases, the Executive Secretary will notify the MC as part of the report and the lists will be updated accordingly.
12 References

[10] PD-08 OIML-CS Procedural Document PD-08: Signing the OIML-CS Declaration